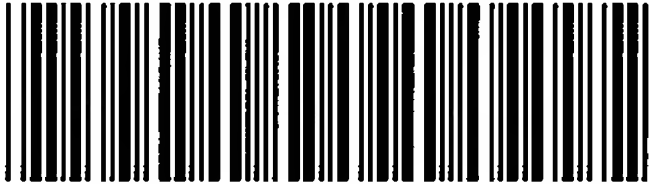


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/602,629	WATANABE, SHIGEKI	
	Examiner	Art Unit	
	John D. Lee	2874	

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359	326-332	2/24/2005	JDL
359	107,108	2/24/2005	JDL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
USPTO "WEST" Database searched; search strategy on separate sheet.	2/24/2005	JDL